

<b>Notice of References Cited</b>	Application/Control No. 10/606,465		Applicant(s)/Patent Under Reexamination POLSON ET AL.	
	Examiner LEON HARPER		Art Unit 2166	Page 1 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,429,879	08-2002	Sturgeon et al.	715/723
*	B	US-6,115,717	09-2000	Mehrotra et al.	707/102
*	C	US-5,929,857	07-1999	Dinallo et al.	715/840
*	D	US-6,925,474	08-2005	McGrath et al.	707/104.1
*	E	US-6,356,914	03-2002	deCarmo et al.	707/104.1
*	F	US-6,518,978	02-2003	Omata et al.	715/723
*	G	US-6,629,104	09-2003	Parulski et al.	707/102
*	H	US-6,708,334	03-2004	deCarmo et al.	718/106
*	I	US-6,138,175	10-2000	deCarmo, Linden A.	710/5
*	J	US-6,760,721	07-2004	Chasen et al.	707/3
*	K	US-7,171,018	01-2007	Rhoads et al.	382/100
*	L	US-7,136,866	11-2006	Springer et al.	707/102
*	M	US-6,829,368	12-2004	Meyer et al.	382/100

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Oetzel et al. Provisional application No. 60/439055 January 2003
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/606,465		Applicant(s)/Patent Under Reexamination POLSON ET AL.	
	Examiner LEON HARPER		Art Unit 2166	Page 2 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,206,853	04-2007	Eytchison et al.	709/230
*	B	US-7,197,234	03-2007	Chatterton, Geoff	386/95
*	C	US-7,116,894	10-2006	Chatterton, Geoff	386/95
*	D	US-6,850,252	02-2005	Hoffberg, Steven M.	715/716
*	E	US-6,684,207	01-2004	Greenfield et al.	707/3
*	F	US-7,447,815	11-2008	Weaver et al.	710/72
*	G	US-7,194,527	03-2007	Drucker et al.	709/220
*	H	US-7,054,888	05-2006	LaChapelle et al.	707/104.1
*	I	US-7,043,477	05-2006	Mercer et al.	707/7
*	J	US-7,096,234	08-2006	Plastina et al.	707/104.1
*	K	US-7,065,527	06-2006	McCartney et al.	707/10
*	L	US-7,051,019	05-2006	Land et al.	707/4
*	M	US-6,983,287	01-2006	Jayanti et al.	707/102

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/606,465		Applicant(s)/Patent Under Reexamination POLSON ET AL.	
	Examiner LEON HARPER		Art Unit 2166	Page 3 of 3

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,941,324	09-2005	Plastina et al.	707/104.1
*	B	US-6,611,607	08-2003	Davis et al.	382/100
*	C	US-7,136,874	11-2006	Mercer et al.	707/104.1
*	D	US-7,159,000	01-2007	Plastina et al.	707/104.1
*	E	US-7,159,233	01-2007	Son et al.	725/86
*	F	US-7,212,574	05-2007	Abrams et al.	375/240.25
*	G	US-7,219,308	05-2007	Novak et al.	715/768
*	H	US-7,220,910	05-2007	Plastina et al.	84/615
*	I	US-7,224,819	05-2007	Levy et al.	382/100
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.